

Radiation Hardened Ultra Low Noise, Precision Voltage Reference

ISL71090SEH25

The ISL71090SEH25 is an ultra low noise, high DC accuracy precision voltage reference with a wide input voltage range from 4V to 30V. The ISL71090SEH25 uses the Intersil Advanced Bipolar technology to achieve sub $2\mu V_{P.P}$ 0.1Hz noise with an accuracy over temperature and radiation of 0.15%.

The ISL71090SEH25 offers a 2.5V output voltage with 10ppm/°C temperature coefficient and also provides excellent line and load regulation. The device is offered in an 8 Ld Flatpack package.

The ISL71090SEH25 is ideal for high-end instrumentation, data acquisition and applications requiring high DC precision where low noise performance is critical.

Applications

- · RH voltage regulators precision outputs
- Precision voltage sources for data acquisition system for space applications
- . Strain and pressure gauge for space applications

Features

• Reference output voltage2.5V±0.05%
Accuracy over temperature and radiation ±0.15%
• Output voltage noise 2µ $V_{P\!-\!P}$ Typ (0.1Hz to 10Hz)
• Supply current 930µA (Typ)
• Tempco (box method) 10ppm/ °C Max
Output current capability 20mA
• Line regulation
• Load regulation2.5ppm/mA
• Operating temperature range55°C to +125°C
Radiation environment
- High dose rate (50-300rad(Si)/s)100krad(Si)
- Low dose rate (0.01rad(Si)/s)100krad(Si)*
- SET/SEL/SEB86MeV•cm ² /mg

^{*}Product capability established by initial characterization. The "EH" version is acceptance tested on a wafer by wafer basis to 50krad(Si) at low dose rate

• Electrically screened to SMD 5962-13211

Related Literature

- AN1847, "ISL71090SEH25 Evaluation Board User's Guide"
- AN1848, "SEE Testing of the ISL71090SEH25"
- AN1849, "Radiation Report of the ISL71090SEH25"

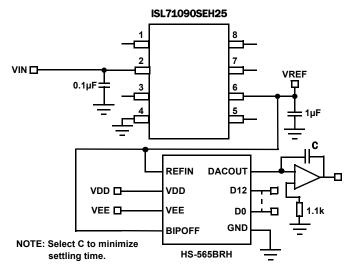


FIGURE 1. ISL71090SEH25 TYPICAL APPLICATION DIAGRAM

1

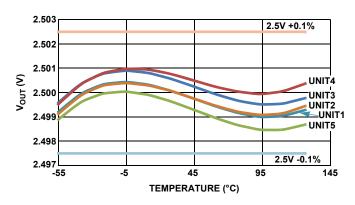


FIGURE 2. V_{OUT} vs TEMPERATURE

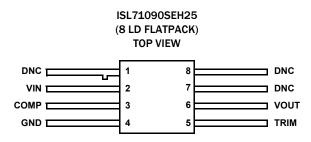
Ordering Information

ORDERING NUMBER (Notes 1, 2, 3)	PART NUMBER	V _{OUT} OPTION (V)	TEMP RANGE (°C)	PACKAGE TAPE & REEL (Pb-Free)	PKG. DWG. #
5962R1321102VXC	ISL71090SEHVF25	2.50	-55 to +125	8 Ld Flatpack	K8.A
ISL71090SEHF25/PR0T0	ISL71090SEHF25/PROTO	2.50	-55 to +125	8 Ld Flatpack	K8.A
ISL71090SEHF25EVAL1Z	Evaluation Board				

NOTES:

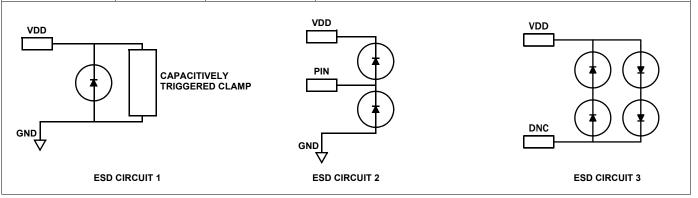
- 1. These Intersil Pb-free Hermetic packaged products employ 100% Au plate e4 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations.
- 2. For Moisture Sensitivity Level (MSL), please see device information page for ISL71090SEH25. For more information on MSL please see tech brief TB363
- 3. Specifications for Rad Hard QML devices are controlled by the Defense Logistics Agency Land and Maritime (DLA). The SMD numbers listed in this "Ordering Information" table must be used when ordering.

Pin Configuration



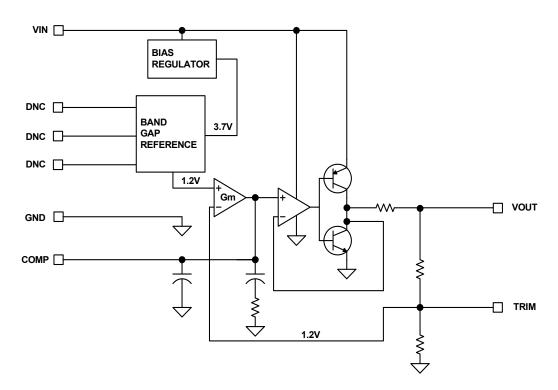
Pin Descriptions

PIN NUMBER	PIN NAME	ESD CIRCUIT	DESCRIPTION
1	DNC	3	Do not Connect
2	VIN	1	Input Voltage Connection
3	COMP	2	Compensation and Noise Reduction Capacitor
4	GND	1	Ground Connection
5	TRIM	2	Voltage Reference Trim input
6	VOUT	2	Voltage Reference Output
7	DNC	3	Do not Connect
8	DNC	3	Do not Connect



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Functional Block Diagram



ISL71090SEH25

Absolute Maximum Ratings

Max Voltage	
V _{IN} to GND	0.5V to +40V
V_{IN} to GND at an LET = 86MeV • cm ² /mg	0.5V to +36V
V _{OUT} to GND (10s)	0.5V to V _{OUT} + 0.5V
Voltage on any Pin to Ground	0.5V to +V _{OUT} + 0.5V
Voltage on DNC PinsNo co	nnections permitted to these pins
Input Voltage Slew Rate (Max)	0.1V/µs
ESD Ratings	
Human Body Model	3kV
Machine Model	200V
Charged Device Model	2kV

Thermal Information

Thermal Resistance (Typical)	$\theta_{JA}(^{c}C/W)$	θ_{JC} (°C/W)
8 Ld Flatpack Package (Notes 4, 5)	140	15
Storage Temperature Range	6	5°C to +150°C
Maximum Junction Temperature (T _{JMAX})		+150°C
Pb-Free Reflow Profile (Note 6)		. see link below
http://www.intersil.com/pbfree/Pb-FreeRe	eflow.asp	

Recommended Operating Conditions

v _{IN}	4.0V to +30V
Temperature Range	55°C to +125°C

CAUTION: Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions may adversely impact product reliability and result in failures not covered by warranty.

NOTES

- 4. θ_{JA} is measured with the component mounted on a high effective thermal conductivity test board in free air. See Tech Brief <u>TB379</u> for details.
- 5. For $\theta_{\text{JC}}\!,$ the "case temp" location is the center of the ceramic on the package underside.
- 6. Post-reflow drift for the ISL71090SEH25 devices can be 100µV typical based on experimental results with devices on FR4 double sided boards. The engineer must take this into account when considering the reference voltage after assembly.
- 7. Product capability established by initial characterization. The "EH" version is acceptance tested on a wafer by wafer basis to 50krad(Si) at low dose rate.
- 8. The output capacitance used for SEE testing is 0.1 μ F for C_{IN} and C_{OUT}.

Electrical Specifications $V_{IN} = 5V$, $I_{OUT} = 0$, unless otherwise specified. Boldface limits apply over the operating temperature range, -55°C to +125°C and radiation.

PARAMETER	DESCRIPTION	CONDITIONS	MIN (Note 9)	TYP	MAX (Note 9)	UNIT
V _{OUT}	Output Voltage	V _{IN} = 5V		2.5		٧
V _{OA}	V _{OUT} Accuracy @ T _A = +25°C (Note 6)	V _{OUT} = 2.5V	-0.05		+0.05	%
V _{OA}	V _{OUT} Accuracy @ T _A = -55°C to +125°C	V _{OUT} = 2.5V	-0.15		+0.15	%
V _{OA}	V _{OUT} Accuracy @ T _A = -55°C to +125°C, Post Rad	V _{OUT} = 2.5V	-0.152		+0.152	%
TC V _{OUT}	Output Voltage Temperature Coefficient (Note 10)				10	ppm/°C
V _{IN}	Input Voltage Range	V _{OUT} = 2.5V	4		30	٧
I _{IN}	Supply Current			0.930	1.28	mA
$\Delta V_{OUT}/\Delta V_{IN}$	Line Regulation	V _{IN} = 4V to 30V, V _{OUT} = 2.5V		8	18	ppm/V
$\Delta V_{OUT}/\Delta I_{OUT}$	Load Regulation	Sourcing: 0mA ≤ I _{OUT} ≤ 20mA		20	35	ppm/mA
		Sinking: -10mA ≤ I _{OUT} ≤ 0mA		40	70	ppm/mA
V _D	Dropout Voltage (Note 11)	V _{OUT} = 2.5V @ 10mA		1.1	1.7	٧
I _{SC+}	Short Circuit Current	T _A = +25°C, V _{OUT} tied to GND		55		mA
I _{SC-}	Short Circuit Current	T _A = +25 °C, V _{OUT} tied to V _{IN}		-61		mA
t _R	Turn-on Settling Time	90% of final value, $C_L = 1.0 \mu F$, $C_C = open$		150		μs
	Ripple Rejection	f = 120Hz		90		dB
e _N	Output Voltage Noise	$0.1Hz \le f \le 10Hz, V_{OUT} = 2.5V$		1.9		μV _{P-P}
V _N	Broadband Voltage Noise	$\textbf{10Hz} \leq \textbf{f} \leq \textbf{1kHz}, \textbf{V}_{\textbf{OUT}} = \textbf{2.5V}$		1.6		μV_{RMS}
	Noise Density	f = 1kHz, V _{OUT} = 2.5V		50		nV/√Hz
$\Delta V_{OUT}/\Delta t$	Long Term Drift	T _A = +125°C, 1000Hrs		15		ppm

NOTES:

- 9. Compliance to datasheet limits is assured by one or more methods: production test, characterization and/or design.
- 10. Over the specified temperature range. Temperature coefficient is measured by the box method whereby the change in V_{OUT} is divided by the temperature range; in this case, = 180°C. (i.e., -55°C to +125°C).
- 11. Dropout Voltage is the minimum $V_{IN} V_{OUT}$ differential voltage measured at the point where V_{OUT} drops 1mV from V_{IN} = nominal at T_A = +25 °C.

FN8451.0
June 6, 2013

Typical Performance Curves $v_{IN} = 5V$, $v_{OUT} = 2.5V$, $T_A = +25$ °C, unless otherwise specified.

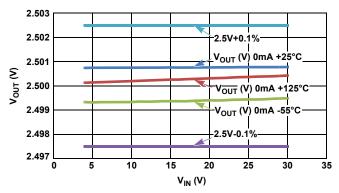


FIGURE 3. V_{OUT} ACCURACY OVER TEMPERATURE

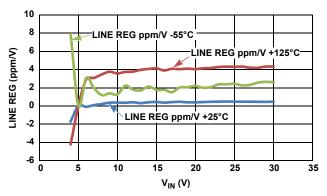


FIGURE 4. LINE REGULATION OVER TEMPERATURE (0mA)

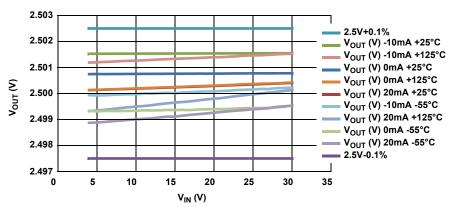


FIGURE 5. V_{OUT} vs V_{IN} AT 0mA, 20mA AND -10mA

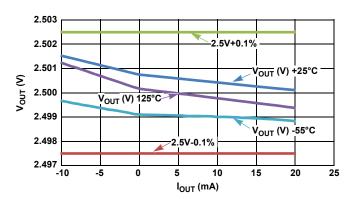


FIGURE 6. LOAD REGULATION OVER TEMPERATURE AT V_{IN} = 5V (V)

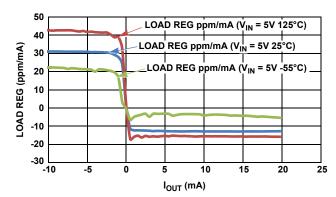


FIGURE 7. LOAD REGULATION OVER TEMPERATURE AT $V_{IN} = 5V$ (ppm/mA)

Typical Performance Curves v_{IN} = 5V, V_{OUT} = 2.5V, T_A = +25 °C, unless otherwise specified. (Continued)

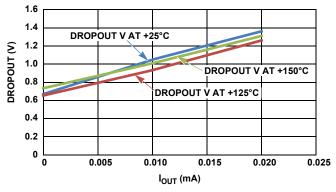


FIGURE 8. DROPOUT VOLTAGE FOR 2.5V

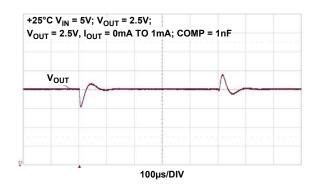


FIGURE 9. LOAD TRANSIENT (0mA TO 1mA)

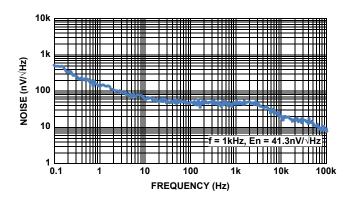


FIGURE 10. NOISE DENSITY vs FREQUENCY ($V_{IN} = 5V$, $I_{OUT} = 0$ mA)

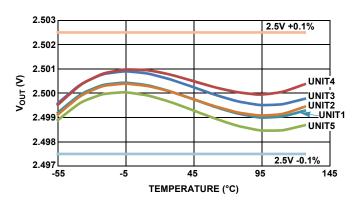


FIGURE 11. TYPICAL TEMPERATURE COEFFICIENT PLOT FOR 5 UNITS

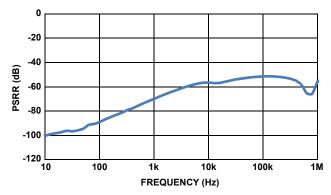


FIGURE 12. PSRR (+25 °C, V_{IN} = 5V, V_{OUT} = 2.5V, I_{OUT} = 0mA, C_{IN} = C_{OUT} = 0.1 μ F, COMP = 1nF, VSIG = 300m $V_{P,P}$)

Device Operation

Bandgap Precision Reference

The ISL71090SEH25 uses a bandgap architecture and special trimming circuitry to produce a temperature compensated, precision voltage reference with high input voltage capability and moderate output current drive.

Applications Information

Board Mounting Considerations

For applications requiring the highest accuracy, board mounting location should be reviewed. The device uses a ceramic flatpack package. Generally, mild stresses to the die when the printed circuit (PC) board is heated and cooled, can slightly change the shape. Because of these die stresses, placing the device in areas subject to slight twisting can cause degradation of reference voltage accuracy. It is normally best to place the device near the edge of a board, or on the shortest side, because the axis of bending is most limited in that location. Mounting the device in a cutout also minimizes flex. Obviously, mounting the device on flexprint or extremely thin PC material will likewise cause loss of reference accuracy.

Board Assembly Considerations

Some PC board assembly precautions are necessary. Normal output voltage shifts of typically 100 μ V can be expected with Pb-free reflow profiles or wave solder on multi-layer FR4 PC boards. Precautions should be taken to avoid excessive heat or extended exposure to high reflow or wave solder temperatures.

Noise Performance and Reduction

The output noise voltage over the 0.1Hz to 10Hz bandwidth is typically $2\mu V_{P-P}$ ($V_{OUT}=2.5V$). The noise measurement is made with a 9.9Hz bandpass filter. Noise in the 10Hz to 1kHz bandwidth is approximately 1.6 μV_{RMS} ($V_{OUT}=2.5V$), with 0.1 μF capacitance on the output. This noise measurement is made with a band pass filter of 990Hz. Load capacitance up to 10 μF (with COMP) can be added but will result in only marginal improvements in output noise and transient response.

Turn-On Time

Normal turn-on time is typically $150\mu s$, the circuit designer must take this into account when looking at power-up delays or sequencing.

Temperature Coefficient

The limits stated for temperature coefficient (Tempco) are governed by the method of measurement. The overwhelming standard for specifying the temperature drift of a reference is to measure the reference voltage at two temperatures which provide for the maximum voltage deviation and take the total variation, $(V_{HIGH} - V_{LOW}),$ this is then divided by the temperature extremes of measurement $(T_{HIGH} - T_{LOW}).$ The result is divided by the nominal reference voltage (at T = +25 $^{\circ}$ C) and multiplied by 10^{6} to yield ppm/ $^{\circ}$ C. This is the "Box" method for specifying temperature coefficient.

Output Voltage Adjustment

The output voltage can be adjusted above and below the factory-calibrated value via the trim terminal. The trim terminal is the negative feedback divider point of the output op amp. The positive input of the amplifier is about 1.216V, and in feedback, so will be the trim voltage. The suggested method to adjust the output is to connect a $1M\Omega$ external resistor directly to the trim terminal and connect the other end to the wiper of a potentiometer that has a $100k\Omega$ resistance and whose outer terminals connect to V_{OUT} and ground. If a $1M\Omega$ resistor is connected to trim, the output adjust range will be ±6.3mV. The TRIM pin should not have any capacitor tied to its output, also it is important to minimize the capacitance on the trim terminal during layout to preserve output amplifier stability. It is also best to connect the series resistor directly to the trim terminal, to minimize that capacitance and also to minimize noise injection. Small trim adjustments will not disturb the factory-set temperature coefficient of the reference, but trimming near the extreme values can.

Output Stage

The output stage of the device has a push pull configuration with an high side PNP and a low side NPN. This helps the device to act as a source and sink. The device can source 20mA and sink 10mA.

Use of COMP Cap

The reference can be compensated for the C_{OUT} capacitors used by adding a capacitor from COMP pin to GND. See Table 1 for recommended values. of the COMP capacitor.

TABLE 1.

C _{OUT} (μF)	С _{СОМР} (nF)
0.1	1
1	1
10	10

SEE Testing

The device was tested under ion beam at an LET of 86MeV • cm²/mg. The device did not latch up or burn out to a VDD of 36V and at +125°C. Single Event transients were observed and are summarized in the Table 2:

TABLE 2.

V _{IN} (V)	l _{out} (A)	С _{оит} (µF)	SET (% V _{OUT})
4	5	1	-4.6
30	5	1	-4.4
30	5	10	-1.0

DNC Pins

These pins are for trimming purpose and for factory use only. Do not connect these to the circuit in any way. It will adversely effect the performance of the reference.

Package Characteristics

Weight of Packaged Device

0. 31 Grams (Typical)

Lid Characteristics

Finish: Gold

Potential: Connected to pin #4 (GND) Case Isolation to Any Lead: 20 x 10⁹ Ω (min)

Die Characteristics

Die Dimensions

1464 μ m x 1744 μ m (58mils x 69mils) Thickness: 483 μ m \pm 25 μ m (19mils \pm 1 mil)

Interface Materials

GLASSIVATION

Type: Nitrox Thickness: 15kÅ

TOP METALLIZATION

Type: AlCu (99.5%/0.5%) Thickness: 30kÅ

BACKSIDE FINISH

Silicon

ASSEMBLY RELATED INFORMATION

SUBSTRATE POTENTIAL

Floating

ADDITIONAL INFORMATION

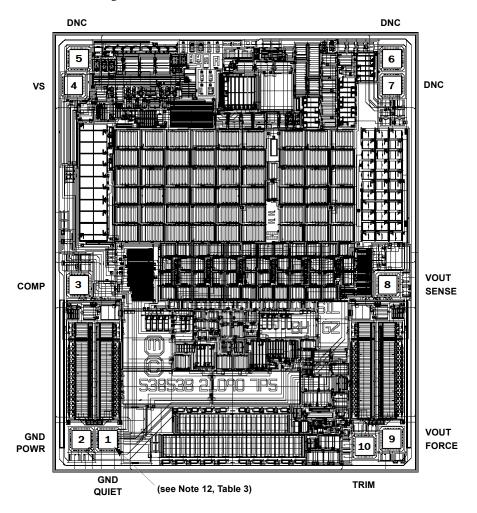
WORST CASE CURRENT DENSITY

 $<2 \times 10^5 \text{ A/cm}^2$

PROCESS

Dielectrically Isolated Advanced Bipolar Technology- PR40

Metallization Mask Layout



ISL71090SEH25

TABLE 3. DIE LAYOUT X-Y COORDINATES

PAD NAME	PIN NUMBER	X (μm)	Υ (μm)	BOND WIRES PER PAD
GND PWR	4	-104	0	1
GND QUIET	4	0	0	1
COMP	3	-108	589	1
VS	2	-125	1350	1
DNC	1	-108	1452	1
DNC	8	1089	1452	1
DNC	7	1089	1350	1
VOUT SENSE	6	1072	598	1
VOUT FORCE	6	1088	1	1
TRIM	5	985	-25	1

NOTES:

- 12. Origin of coordinates is the centroid of GND QUIET.
- 13. Bond wire size is 1 mill.

Revision History

The revision history provided is for informational purposes only and is believed to be accurate, but not warranted. Please go to the web to make sure that you have the latest revision.

DATE	REVISION	CHANGE
June 6, 2013	FN8451.0	Initial Release.

About Intersil

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For the most updated datasheet, application notes, related documentation and related parts, please see the respective product information page found at www.intersil.com/en/support/ask-an-expert.html. Reliability reports are also available from our website at http://www.intersil.com/en/support/qualandreliability.html#reliability

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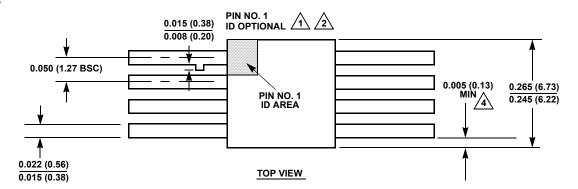
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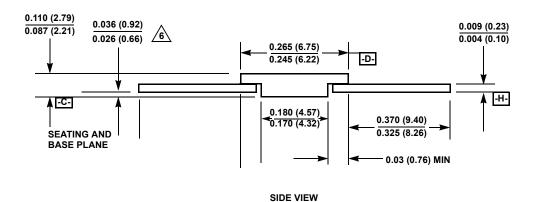
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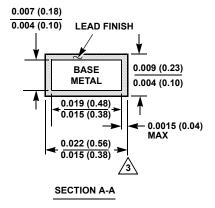
Package Outline Drawing

8 LEAD CERAMIC METAL SEAL FLATPACK PACKAGE

Rev 3, 3/13







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NOTES:

1. Index area: A notch or a pin one identification mark shall be located adjacent to pin one and shall be located within the shaded area shown. The manufacturer's identification shall not be used as a pin one identification mark. Alternately, a tab may be used to identify pin one.

 $\sqrt{2}$ If a pin one identification mark is used in addition to a tab, the limits of the tab dimension do not apply.

The maximum limits of lead dimensions (section A-A) shall be measured at the centroid of the finished lead surfaces, when solder dip or tin plate lead finish is applied.

Measure dimension at all four corners.

For bottom-brazed lead packages, no organic or polymeric materials shall be molded to the bottom of the package to cover the leads.

6. Dimension shall be measured at the point of exit (beyond the meniscus) of the lead from the body. Dimension minimum shall be reduced by 0.0015 inch (0.038mm) maximum when solder dip lead finish is applied.

- 7. Dimensioning and tolerancing per ANSI Y14.5M 1982.
- 8. Controlling dimension: INCH.

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